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CONFIRMATION NO. 3295

<b>SERIAL NUMBER</b> 10/751,525	<b>FILING or 371(c) DATE</b> 01/06/2004 <b>RULE</b>	<b>CLASS</b> 714	<b>GROUP ART UNIT</b> 2117	<b>ATTORNEY DOCKET NO.</b> 60188-725		
<b>APPLICANTS</b> Mitsuyasu Ohta, Osaka, JAPAN; Sadami Takeoka, Osaka, JAPAN; Toshihiro Hiraoka, Osaka, JAPAN; <b>** CONTINUING DATA *****</b> This application is a CON of 09/381,377 09/20/1999 PAT 6,708,301 which is a 371 of PCT/JP98/01249 03/20/1998 <b>** FOREIGN APPLICATIONS *****</b> JAPAN 9-067667 03/21/1997 <b>** IF REQUIRED, FOREIGN FILING LICENSE GRANTED **</b> 04/08/2004						
Foreign Priority claimed <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No 35 USC 119(a-d) conditions met <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No Verified and Acknowledged <u>/CYNTHIA H BRITT/</u> Examiner's Signature		<input type="checkbox"/> Met after Allowance Initials	<b>STATE OR COUNTRY</b> JAPAN	<b>SHEETS DRAWINGS</b> 22	<b>TOTAL CLAIMS</b> 21	<b>INDEPENDENT CLAIMS</b> 3
<b>ADDRESS</b> McDermott, Will & Emery 600 13th Street, N.W. Washington, DC 20005-3096 UNITED STATES						
<b>TITLE</b> Functional block for integrated circuit, semiconductor integrated circuit, method for testing semiconductor integrated circuit, and method for designing semiconductor integrated circuit						
<b>FILING FEE RECEIVED</b> 788	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:			<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit		